

Electromechanical instability in suspended carbon nanotubes

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We have theoretically investigated electromechanical properties of freely suspended carbon nanotubes when a current is injected into the tubes using a scanning tunneling microscope. We show that a shuttle-like electromechanical instability can occur if the bias voltage exceeds a dissipation-dependent threshold value. An instability results in large amplitude vibrations of the carbon nanotube bending mode, which modify the current-voltage characteristics of the system.

Nanoelectromechanical systems (NEMS) have been a subject of extensive research in recent years. The possibility of combining electrical and mechanical degrees of freedom on the nanoscale may give rise to technological advantages as well as manifestations of fundamental physical phenomena. From a technological point of view the interest is largely due to the many applications that may be realized using NEMS.¹ Among the many NEMS phenomena of considerable physical interest, we focus in this Letter on the “shuttle” instability that is expected to occur in a specific class of systems. This phenomenon was predicted by Gorelik *et al.*² and have been theoretically investigated in a number of publications, see Shekhter *et al.*³ for a review. The typical shuttle system consists of a movable conducting grain placed in an elastic medium between two metallic leads. When the system is DC-biased over a certain threshold, an electromechanical instability occurs, resulting in large-amplitude mechanical vibrations and a shuttle current proportional to the vibration frequency. Different experimental approaches have been used to build and investigate various versions of this system.^{7,8} However, some problems persist and a true shuttle instability has not been observed. Carbon nanotubes (CNT) are materials that have proved to be strong candidates for building NEMS. The electrical properties of CNTs depend on their detailed structure and the mechanical properties are extraordinary. A very high Young’s modulus and low mass give typical resonance frequencies in the GHz-regime and the tubes can be mechanically deformed without breaking. Progress in fabrication of CNTs shows that it is possible to build structures, for example suspended tubes^{9,10,11} and nanorelays,¹² where CNT mechanical degrees of freedom are important. The work presented here was done in response to recent experimental progress by LeRoy *et al.*⁹ in measurements on suspended carbon nanotubes (CNT) using a scanning tunneling microscope (STM). Peaks in the $dI/dV - V$ characteristics when current is injected into the free hanging part of the nanotube are attributed to inelastic tunneling of electrons that interact with the radial breathing mode (RBM) of the tube. This is a manifestation of a coupling between the electronic and mechanical degrees of freedom in the system, allowing for additional channels of charge transport through

the system by means of vibronic assisted tunneling. We would like to point out that in addition a different electromechanical effect — an electromechanical shuttle-like instability — may occur in the system. Such an instability occurs when the ground state is unstable with respect to small spatial deviations of the nanotube from its equilibrium position. Small displacements grow in time and develop into limit cycle oscillations that modify the transport properties. The shuttle instability is fundamentally different from vibronic assisted tunneling, in the sense that it results in a condensate of coherent phonons⁵ and hence large-amplitude mechanical bending mode vibrations. Below we will show that a shuttle-like instability may indeed occur in the suspended CNT-structure. It may therefore be a useful experimental system for investigating shuttling phenomena, also in the quantum regime. Quantum effects are expected to be important if the amplitude ΔX_0 of the zero-point bending-mode oscillations is at least as large as the tunneling length $\lambda \sim 0.5 \text{ \AA}$ — a length that characterizes the tunnel barrier separating the STM tip and the nanotube. Theoretically, the shuttle system has been modeled in both the quasi-classical⁴ and the quantum mechanical limits,^{5,6} while so far the quantum regime has not been experimentally accessible. We will show below that the suspended CNT structure is the best candidate system for experiments that probe the quantum regime of shuttling.

In the present work we investigate a system where an STM-tip is used to measure the current through a suspended CNT as in the experiment by LeRoy *et al.*⁹ We use the model system depicted in Figure 1 and consider a metallic CNT (single or multi-wall) suspended over a trench. The nanotube is treated as a classical continuum beam with length l , inner radius r_i and outer radius r_o . An STM-tip is positioned near the center of the trench in close proximity to the nanotube; the distance from the undeformed tube to the tip is $L \sim 1 \text{ nm}$. The STM acts as an electrode, which is connected to the tube by a tunnel junction. The STM-tube separation is not fixed but depends on the deflection X of the tube from the equilibrium straight position. Both the resistance R_1 and the capacitance C_1 characterizing this junction are functions of this parameter. The ends of the tube rest on electrodes to which they are electrically connected via

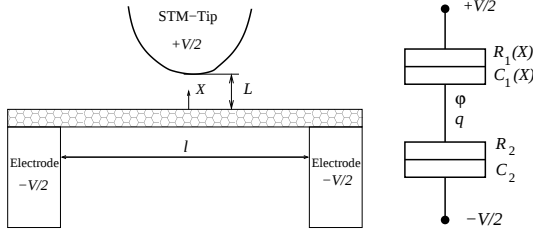


Figure 1: Model system (left) and equivalent circuit (right). A carbon nanotube of length l is suspended over a trench; the tube ends are connected to metal electrodes. The tube can be mechanically deformed and X measures the deflection of the center of the tube from its equilibrium position. An STM-tip is positioned a distance L above the center of the tube and a DC-bias voltage V is applied between the STM and the electrodes. The CNT is treated as a metallic island with excess charge q and electrostatic potential ϕ . The STM-tube contact is a tunnel junction characterized by resistance $R_1(X)$ and capacitance $C_1(X)$. The contacts between tube and electrodes are also tunnel junctions, characterized by a constant resistance R_2 and a constant capacitance C_2 .

tunnel junctions rather than ohmic contacts – the most likely scenario for CNT-metal junctions. The parameters for these junctions can be described by a single constant capacitance C_2 and a single constant resistance R_2 . A DC-bias voltage V is applied between the STM and the electrodes. The time scale for charge redistribution in the tube is fast compared to other time scales in the system allowing one to treat the nanotube as a metallic island with an excess charge q and electrostatic potential ϕ . A capacitive force F_{cap} that depends on the potential drop between the STM and the CNT attracts the tube toward the STM-tip.

We first discuss the possibility for an electromechanical instability to occur in our model system. For this purpose we restrict ourselves to the case when $R_1 \sim R_2$ in equilibrium. Because capacitances are not strongly dependent on geometry, we furthermore neglect the variation of the capacitance with position. Since R_1 depends exponentially on X , $R_2 \gg R_1$ when the tube-STM separation decreases significantly on the scale of the tunneling length and $R_1 \gg R_2$ when the separation increases significantly. This implies that when the tube is close to the STM-tip, the time scale τ_1 for charge exchange between the STM and the tube is much shorter than the time scale τ_2 for charge exchange between the tube and the electrodes. Hence, the potential on the tube approaches the STM-potential. In the opposite limit, when the tube is far from the STM, $\tau_1 \gg \tau_2$ the tube potential approaches the potential of the electrodes. Consider now oscillations with frequency ω so that the tube position alternates between these limiting values. Finite values of the parameters $\omega\tau_{1,2}$ lead to retardation, which implies that the potential on the tube does not have time to reach its equilibrium value determined solely by the tube position. Rather, the potential depends on the tube position at earlier times as well, *i.e.* on the tube velocity and ex-

ceeds the equilibrium value when the tube moves away from the tube and vice versa. It follows that the force on the tube is correlated with the tube velocity, $\dot{X}F_{\text{cap}} \neq 0$, and that mechanical work will be performed on the tube during the oscillatory motion.

These qualitative arguments show that the necessary force-velocity correlation for an instability to occur will develop. However, the performed work must be positive and large enough to exceed the energy that can be dissipated. If this condition is met, a small deviation from the equilibrium position of the tube grows in time and results in limit cycle oscillations. The instability will change the current flow through the system, the nature of this change will be discussed below.

To support the qualitative arguments, we have made quantitative calculations for our model, focussing on the fundamental bending mode of the doubly clamped nanotube. The eigenfrequency of this mode can be obtained from linear elasticity theory as $\omega \approx (22.4/l^2)\sqrt{EI/\rho S}$, where E is the Young's modulus of the CNT, typically of order^{14,15} 1 TPa, $I = \frac{\pi}{4}(r_o^4 - r_i^4)$ is the area moment of inertia of the cross section, ρ is the mass density and S is the tube cross-section area. Excitation of the fundamental bending mode can be described by a single parameter $X(t)$, which denotes the deflection of the center of the tube from its equilibrium position. In the limit of small deflections ($X \ll l$) the potential energy of the bent tube can be expressed as $U = kX^2/2$, where k is an effective spring constant for the tube. Hence, the equation of motion for the mechanical degree of freedom is

$$m_{\text{eff}}\ddot{X} + \gamma\dot{X} + kX = F_{\text{cap}}. \quad (1)$$

The effective mass of the tube $m_{\text{eff}} = k/\omega^2 \approx 0.4m_{\text{tot}}$ in eq 1 is proportional to the total tube mass m_{tot} and a phenomenological viscous damping $\gamma\dot{X}$ characterized by a quality factor $Q = \omega m_{\text{eff}}/\gamma$ has been introduced. To evaluate the capacitive force we use model capacitances for the junctions. The STM-tube junction is approximated by a parallel plate capacitance $C_1 = C_0/(1 - X/L)$, where C_0 is the typical capacitance between the STM and the tube and L is the equilibrium STM-tube separation. The tube-electrodes capacitance C_2 is a constant.

It is convenient to work with the excess charge q on the tube as a variable instead of the tube potential. The capacitive force then takes the form $F_{\text{cap}} = F_0(C_2V - q)^2/(1 - \alpha X)^2$, where F_0 depends on the capacitances and $\alpha \sim 1/L$. Charge is treated as a continuum variable, which is valid if the charge exchange rate is high and the temperature not too low. Using an exponential form for the STM-tube resistance, $R_1(X) = R_0 \exp(-X/\lambda)$, we derive a differential equation for the time evolution of the charge according to

$$\dot{q} = \frac{V}{2} \left(G_- - \frac{C_-}{C_\Sigma} G_\Sigma \right) - q \frac{G_\Sigma}{C_\Sigma}, \quad (2)$$

where $C_\Sigma(X) = C_1(X) + C_2$ and $C_- = C_1(X) - C_2$ are the sum and difference of the junction capacitances and

$G_{\Sigma}(X) = 1/R_1(X) + 1/R_2$ and $G_- = 1/R_1(X) - 1/R_2$ are the sum and difference of their conductances.

Equations 1 and 2 define our model system, which we will now analyze both analytically and numerically. Defining (X_0, q_0) as their steady state solution we linearize these equations with respect to small deviations from the steady state. We find that a deviation grows with time for fixed V if the dissipation is below a threshold value γ_{thr} . This implies that a shuttle-like instability does occur in the system. However, the threshold dissipation is not a positive definite function of the system parameters and if it is negative no instability will occur. In this case the force-velocity correlation leads to intrinsic dissipation in the system, which suppresses any mechanical deviation and prevents an instability from developing. This effect originates from the position dependence of the STM-tube capacitance, which contributes a term to the force-velocity correlation that has the opposite sign compared to the term coming from the position dependence of the resistance. Since capacitances are not strongly dependent on geometry ($L \gg \lambda$), the correlations due to the change in resistance usually dominates. Only in the limit $R_2 \gg R_0$ does the position dependence of the capacitance become important since the potential of the tube is then close to the STM-potential and the voltage drop over the STM-tube junction does not change appreciably with tube position.

We can investigate the threshold dissipation analytically in various limits. We find that the threshold dissipation goes to zero in the limits $(R_0 \rightarrow 0, R_2 \rightarrow 0)$, $(R_0 \rightarrow \infty, R_2 \rightarrow \infty)$ and $R_0 \rightarrow \infty$ while it approaches a negative value if $R_2 \rightarrow \infty$. First consider the limit $(R_0 \rightarrow 0, R_2 \rightarrow 0)$ which implies $(\omega\tau_1 \rightarrow 0, \omega\tau_2 \rightarrow 0)$ and a sufficiently fast charge exchange rate for the tube potential to always have its equilibrium value. Retardation is negligible and no mechanical work is performed on the tube. In the limit $(R_0 \rightarrow \infty, R_2 \rightarrow \infty)$, $(\omega\tau_1 \rightarrow \infty, \omega\tau_2 \rightarrow \infty)$ charge exchange is a slow process and the tube potential is approximately constant during tube oscillations, making retardation a small effect also in this limit. Finally, in the limits $R_0 \rightarrow \infty$ or $R_2 \rightarrow \infty$, we have $\omega\tau_2 \gg \omega\tau_1$ or $\omega\tau_2 \gg \omega\tau_1$, respectively, and the potential on the tube is mainly determined by the coupling to the electrodes or the STM. The latter case leads to dissipation as discussed previously and the former leads to a small force-velocity correlation since corrections to the equilibrium potential is small.

Our qualitative analysis suggests that optimal conditions for an instability can be found in a symmetric setup where $R_0 \sim R_2$. The threshold dissipation for a typical set of parameters¹⁸ is plotted as a function of junction resistances in Figure 2, where a region of optimal conditions for the instability can be identified. This region corresponds to a symmetric case, where $\omega\tau_1 \sim \omega\tau_2 \sim 1$, in support of the qualitative conclusion that resistances of the same order of magnitude are optimal. Because of this, we do expect poor conditions for an instability in the experiment by LeRoy *et al.*⁹ since their junction

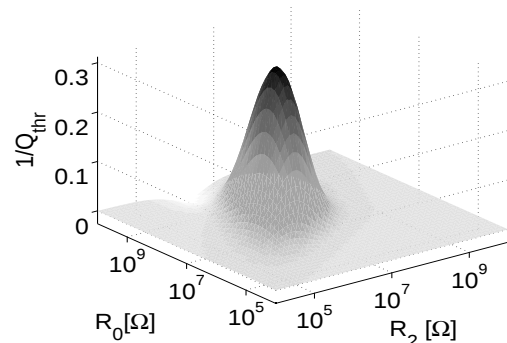


Figure 2: Threshold dissipation as a function of junction resistances for $V = 1$ V. Dissipation is proportional to $1/Q$, the inverse quality factor for mechanical oscillations, and an instability occurs if $1/Q < 1/Q_{\text{thr}}$. Large values of $1/Q_{\text{thr}}$ correspond to optimal conditions for an instability to occur, and are found when the junction resistances are of the same order of magnitude. In the limit of highly asymmetric junctions $1/Q_{\text{thr}}$ is small.

resistances are highly asymmetric.

The above arguments show that the occurrence of a shuttle-like electromechanical instability for a fixed voltage crucially depends on the Q-factor of the bending mode vibrations and the junction parameters. Experimental Q-values of the order of $10^1 - 10^3$ have been reported for CNTs,^{11,13} corresponding to weak dissipation and an instability feasible with bias voltages smaller than 1 V for a large range of parameters.

In order to investigate the instability in more detail we solve the system of equations 1 and 2 numerically for different bias voltages using a typical set of parameters.¹⁸ The results confirm the analytical conclusions, i.e. if the voltage exceeds a certain threshold an electromechanical instability occurs unless the threshold dissipation is negative. The amplitude of the limit cycle mechanical vibrations is shown as a function of bias voltage in Figure 3, where a threshold is clearly visible when the vibration amplitude A becomes non-zero. The instability is associated with different characteristics depending on the type of transition. The vibration amplitude is either a step function of voltage (hard excitation) or a smooth function (soft excitation). In the case of a hard excitation the current will be a step-like function of voltage, whereas a soft excitation leads to a jump in the first derivative of the current. This can be seen in Figure 4, where the $I - V$ and the $dI/dV - V$ curves corresponding to the instabilities in Figure 3 are shown.

As we have seen, the electromechanical instability changes the transport properties of the system, leading to a step in the $I - V$ or $dI/dV - V$ characteristics depending on the type of transition that occurs. These are features that may be used to detect the instability. Furthermore, theoretical studies of the current noise in the ordinary shuttle² have shown that the instability is

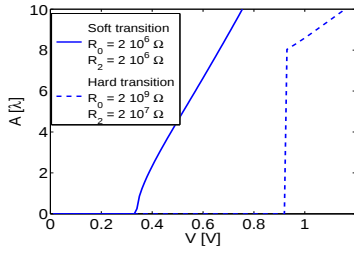


Figure 3: An electromechanical instability occurs when the bias voltage exceeds a threshold value, which results in bending mode vibrations of the nanotube with amplitude A . The amplitude either increases smoothly (solid line) or in a step-like fashion (dashed line) as a function of voltage. Here $Q = 50$.

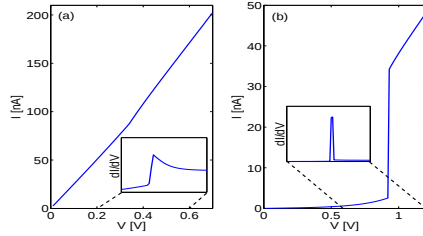


Figure 4: $I - V$ characteristics corresponding to the soft (a) and the hard (b) transition in Figure 3. Insets depict the $dI/dV - V$ characteristics in the vicinity of the threshold voltage. The soft transition manifests itself as a jump in the value of dI/dV , whereas the hard transition gives rise to a peak in the $dI/dV - V$ -curve.

associated with an increase of current noise.¹⁶ Since we expect a shuttle-like instability in the CNT system to result in a qualitatively similar noise increase, noise measurements may also be used to identify the instability. A third approach to detecting the instability is to apply a small modulation to the bias voltage in analogy with the Sazonova *et al.* mixing experiment.¹¹

Quantum effects in shuttling have been considered theoretically^{5,6}, but they have so far not been accessible by experiments. With the suspended CNT system one can control the amplitude of the zero point oscillations by changing the length of the tube. It should therefore be

possible to experimentally probe the regime where quantum effects are important by using longer tubes. An estimate of the ratio $2\Delta X_0/\lambda$ — of order one or larger in the quantum regime — for different parameters shows it to be in the range $(0.5 - 1) (l/\mu\text{m})^{1/2}$ for a single wall carbon nanotube. This is a larger value than can be estimated for other realizations of the shuttle *e.g.* one finds $2\Delta X_0/\lambda \sim 0.2 - 0.3$ in the C_{60} -SET device used by Park *et al.*⁸ The suspended CNT-shuttle is so far the system where quantum corrections will be most significant.

The typical STM-tube separation is of order 1 nm and, consequently, surface forces between the tube and the STM will be important. However, the influence of these forces is mainly quantitative, it does not change the qualitative conclusion that an instability occurs. The scale of these forces for interactions between a CNT and a metallic electrode is¹⁷ of the order of a few nN. In the suspended CNT-structure the scale of the elastic forces can be changed by orders of magnitude by varying the tube length and thickness. Consequently, the importance of the surface forces relative to the elastic forces depends on the tube geometry.

To conclude, we propose that a shuttle-like electromechanical instability can be experimentally studied by using suspended carbon nanotubes in tunneling contact with supporting metal electrodes and an STM tip. We support this claim with an analysis of a classical model of such a system and seek the optimal conditions for an instability to occur. The shuttle-like instability is most likely to occur in the symmetric case, when all the tunneling resistances are of the same order of magnitude. We demonstrate that the effect of the instability is to change the $I - V$ characteristics and, finally, we show that the suspended nanotube system is the first, where the quantum regime may be approached experimentally.

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